

Notice of References Cited	Application/Control No. 09/834,830		Applicant(s)/Patent Under Reexamination HEINEN ET AL.	
	Examiner Mark A Mais		Art Unit 2664	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,594,275 B1	07-2003	Schneider, Thomas R.	370/465
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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